

<i>Generation</i>	<i>I</i>	<i>II</i>	<i>III</i>	<i>IV</i>	<i>This new version</i>
<i>Name</i>	<i>Quickly Scheduler</i>	<i>DLD</i>	<i>On-line DLD</i>	<i>On-line DLD</i>	<i>On-line DLD</i>
<i>System Type</i>	<i>Off-line</i>	<i>On-line, Real Time</i>	<i>On-line, Real Time</i>	<i>On-line, Real Time</i>	<i>On-line, Real Time</i>
<i>Algorithm Type</i>	<i>Heuristic Algorithm</i>	<i>Multi-Priority Factor</i>	<i>Multi-Priority Factor</i>	<i>Multi-Dispatching Algorithm</i>	<i>Multi-Dispatching Algorithm</i>
<i>Date Care MPS</i>	<i>No</i>	<i>Yes</i>	<i>Yes</i>	<i>Yes</i>	<i>Yes</i>
<i>Date Care Lot Due Date</i>	<i>Yes</i>	<i>Yes</i>	<i>Yes</i>	<i>Yes</i>	<i>Yes</i>
<i>Dispatching Subject</i>	<i>Production Lot</i>	<i>Production Lot</i>	<i>Production Lot and Engineering Lot</i>	<i>Production Lot and Engineering Lot</i>	<i>Production Lot and Engineering Lot</i>
<i>Dispatching Subject Type</i>	<i>Wafer</i>	<i>Wafer</i>	<i>Wafer and PKG</i>	<i>Wafer and PKG</i>	<i>Wafer and PKG</i>
<i>Dispatching Subject Stage</i>	<i>Test-INV/Sort1/Sort2</i>	<i>Sort1/Sort2</i>	<i>Test-INV/Sort1/Sort2/FT-BANK/F-Test/LINKING</i>	<i>Test-INV/Sort1/Sort2/FT-BANK/F-Test/LINKING</i>	<i>Test-INV/Sort1/Sort2/FT-BANK/F-Test/LINKING</i>
<i>Date Care Production</i>	<i>None</i>	<i>P/C</i>	<i>P/C, L/B for Wafer and L/B for PKG</i>	<i>P/C, L/B for Wafer and L/B for PKG</i>	<i>P/C, L/B for Wafer and L/B for PKG</i>
<i>Production Apparatus Type</i>	<i>None</i>	<i>For single device apparatus behavior</i>	<i>For multi-devices using the same apparatus behavior</i>	<i>For multi-devices using the same apparatus behavior</i>	<i>For multi-devices using the same apparatus behavior</i>
<i>Scale in Taking Care Setup Time</i>	<i>Only take care the same PART ID to reduce setup time</i>	<i>Only take care the same PART ID to reduce setup time</i>	<i>[Don't change test program] > [Don't change P/V] > {Don't change L/B} > [Don't change production type CP, FT]</i>	<i>[Don't change test program] > [Don't change P/V] > {Don't change L/B} > [Don't change production type CP, FT]</i>	<i>[Don't change test program] > [Don't change P/V] > {Don't change L/B} > [Don't change production type CP, FT]</i>
<i>Date Care Hardware and Software Special Constraint Information</i>	<i>None</i>	<i>Take care them as planning problem on exception rule system</i>	<i>Take care them as planning problem on exception rule system</i>	<i>Line PROMIS constraint function to take care them, and DLD exception rule system rule only for planning problem</i>	<i>PROMIS</i>
<i>MES Environment</i>	<i>PROMIS</i>	<i>POSIDOM</i>	<i>POSIDOM</i>	<i>POSIDOM</i>	<i>PROMIS</i>
<i>Performance</i>	<i>Off-line system running 10 min, & manual tuning 4 hrs for all tester one day dispatching</i>	<i>Around 5 sec for one tester next dispatching lot</i>	<i>Around 7 sec for one tester next dispatching lot</i>	<i>FIG. 1</i>	<i>Around 7 sec for one tester next dispatching lot</i>

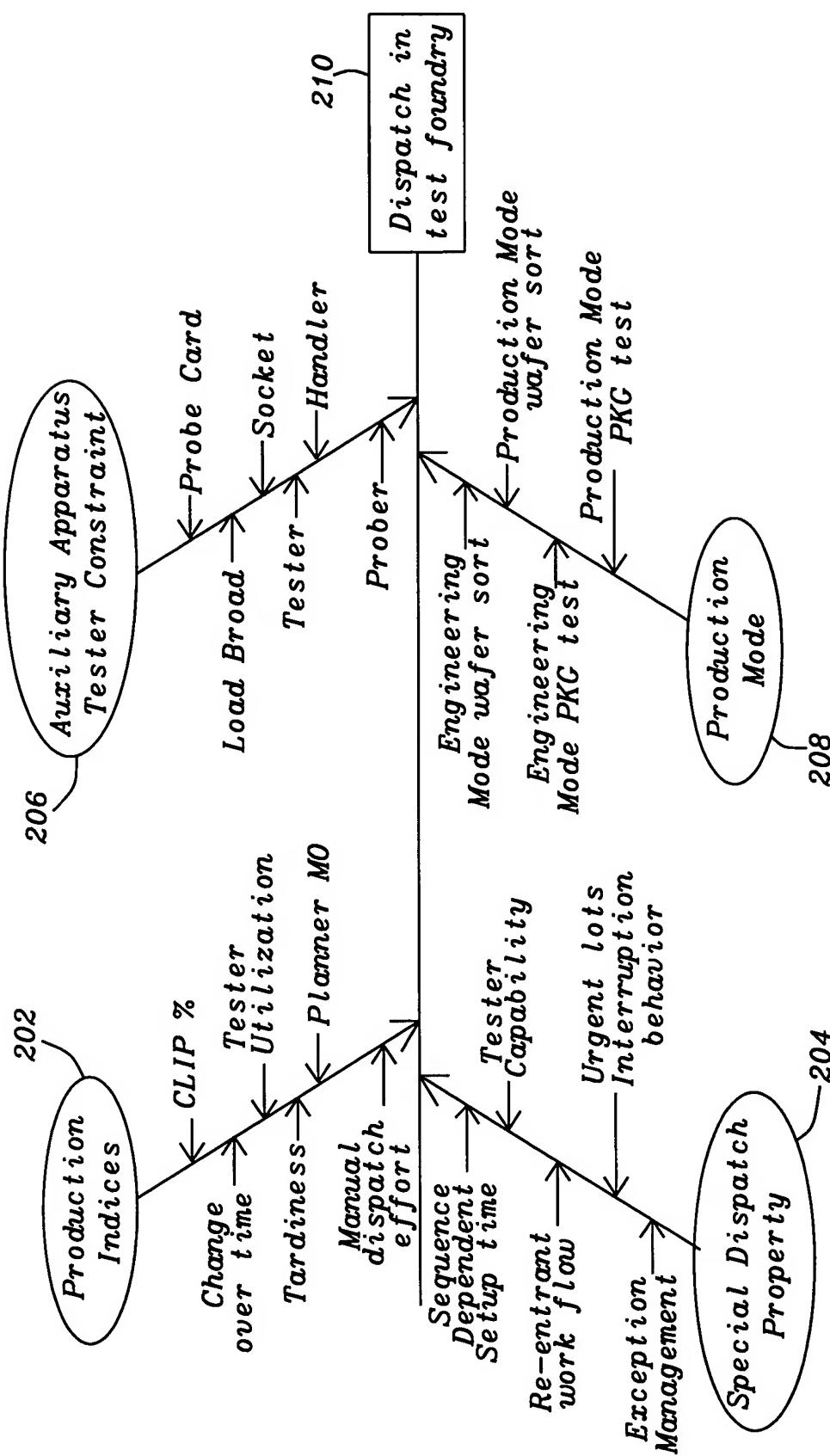
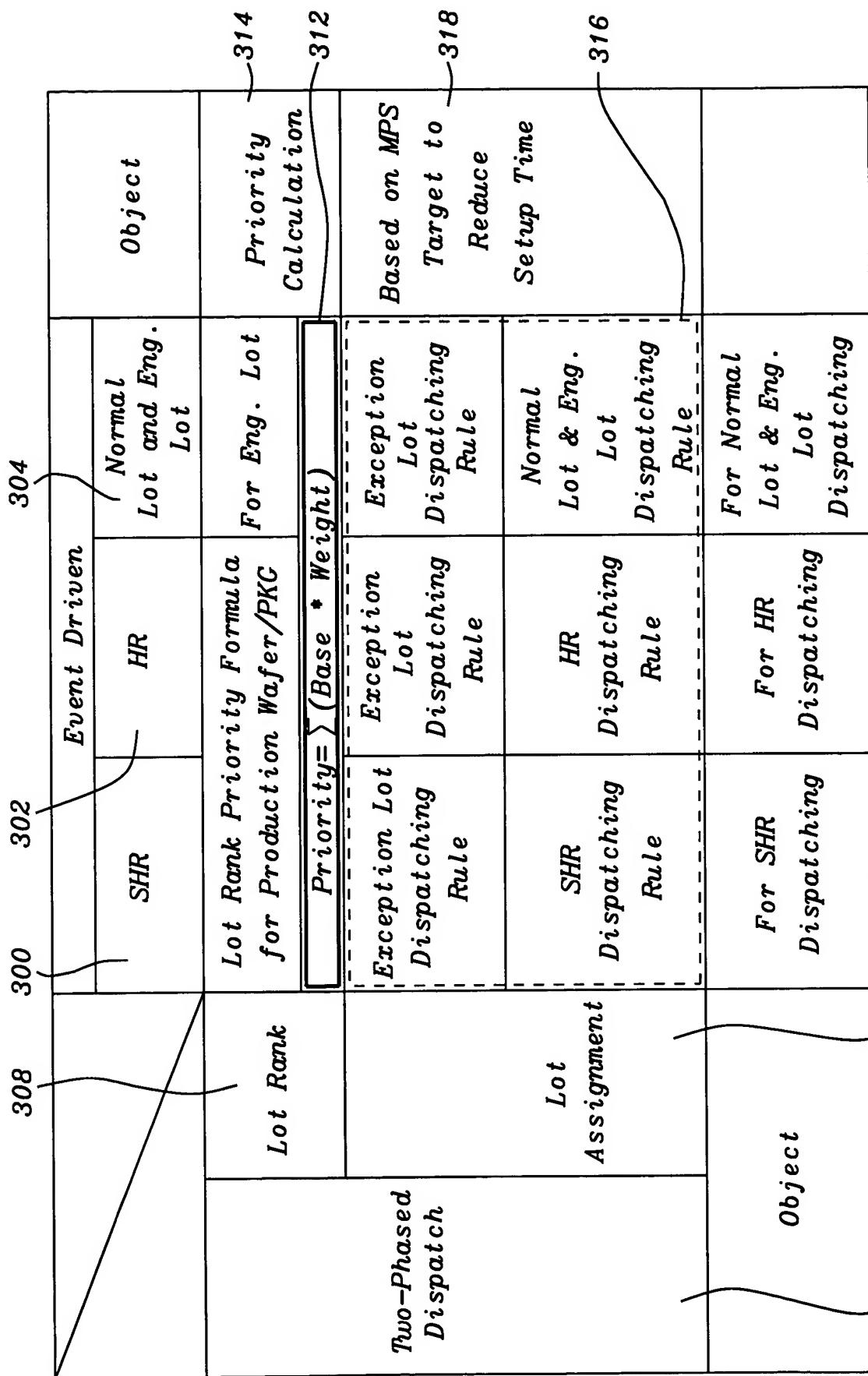
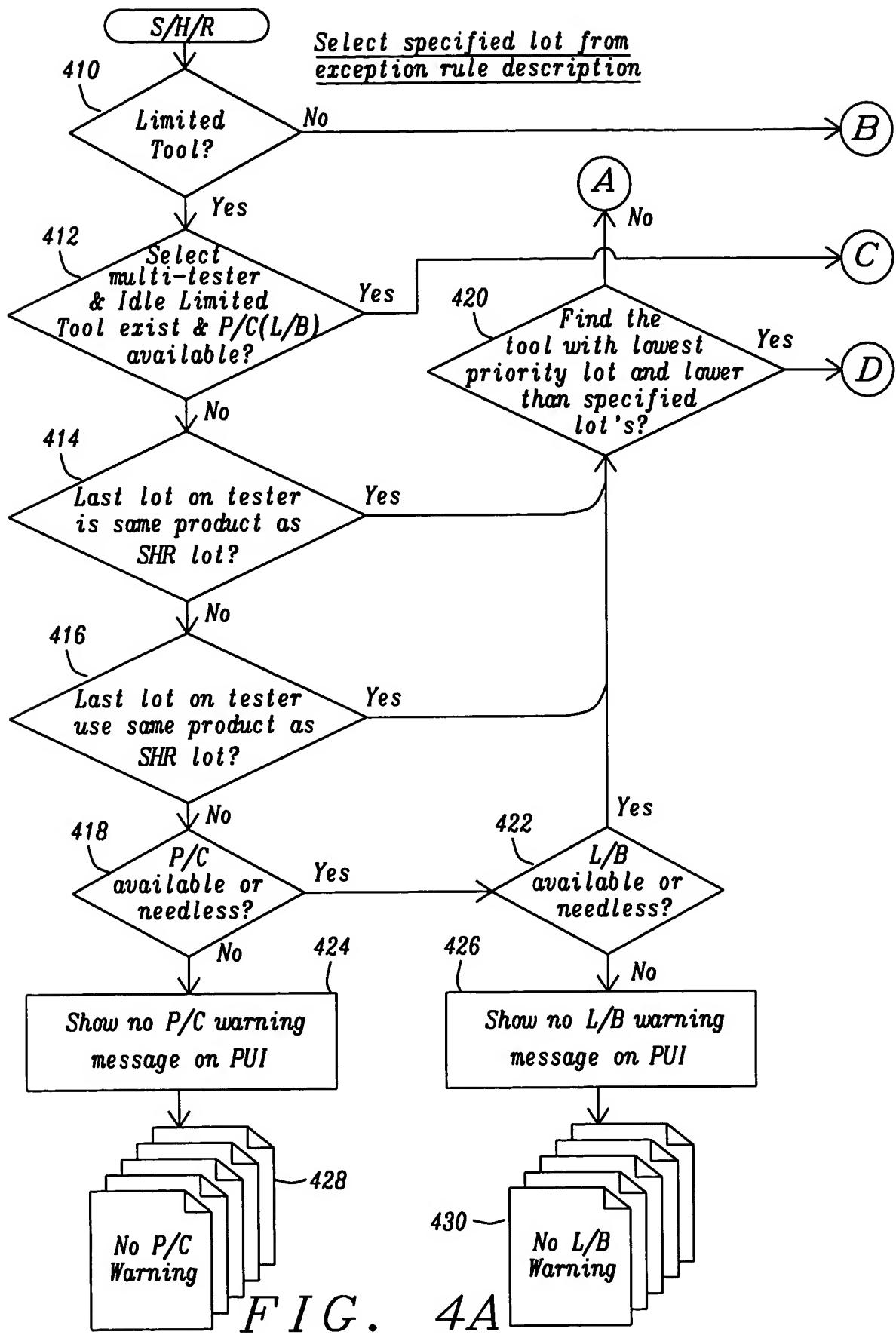
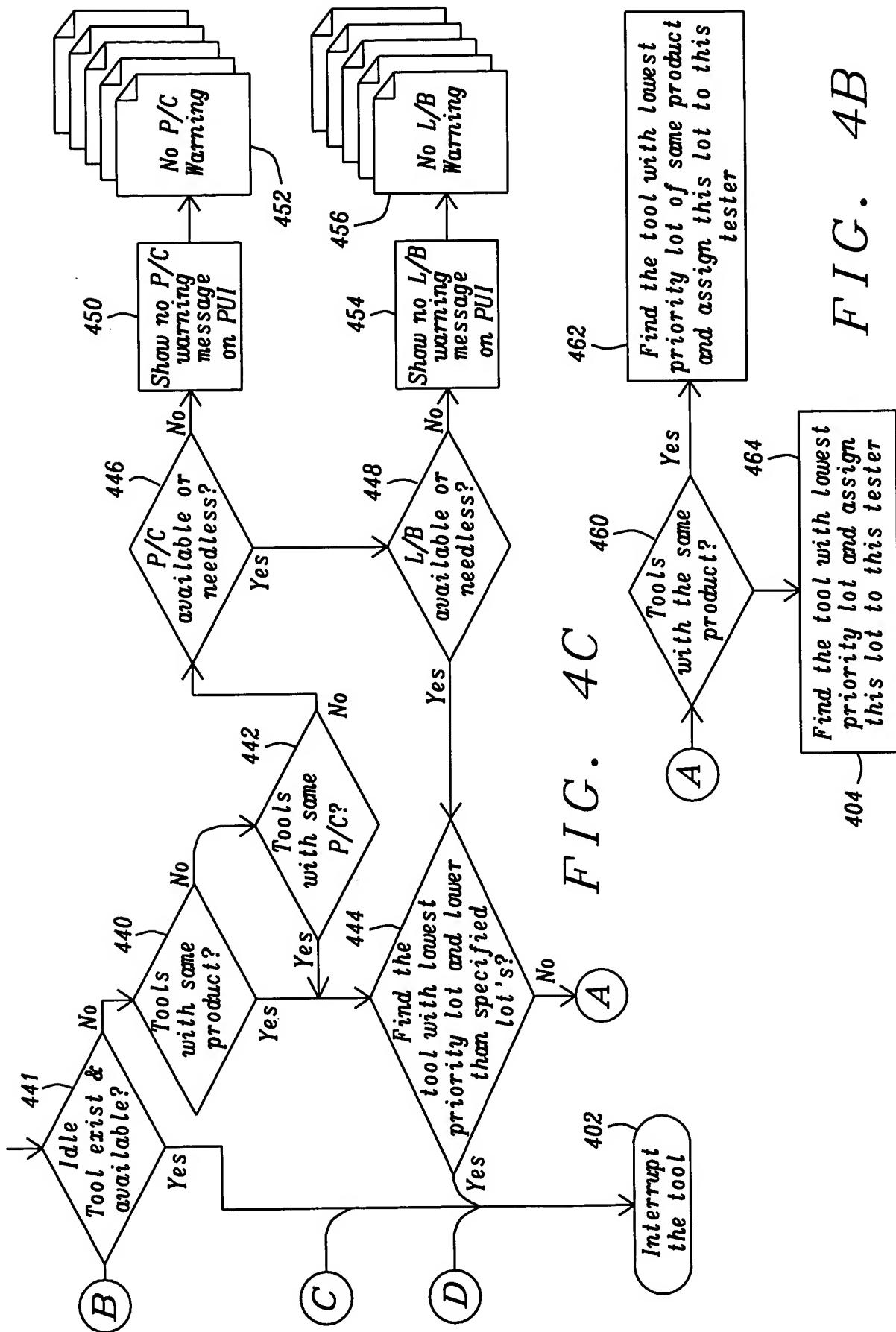
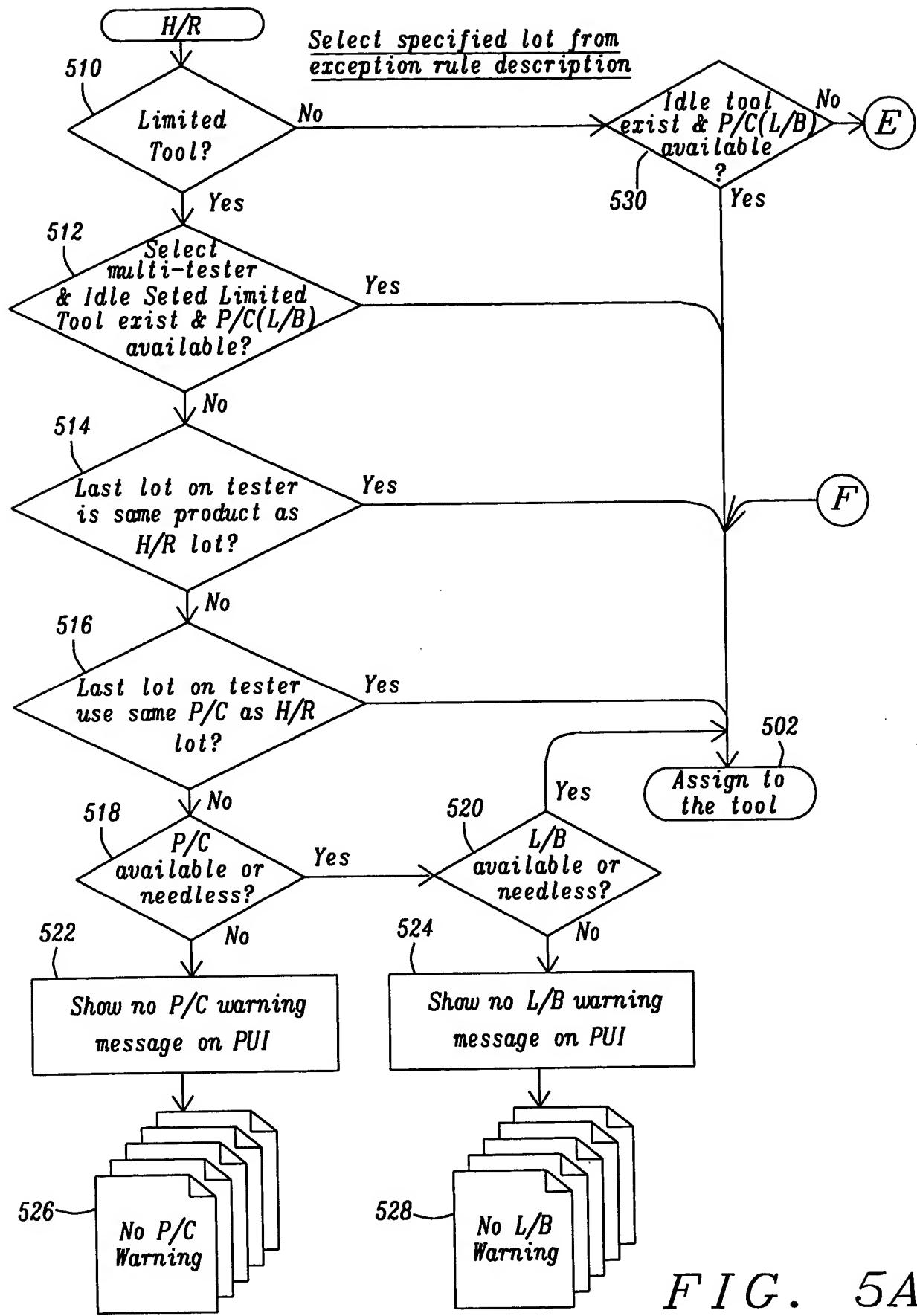


FIG. 2









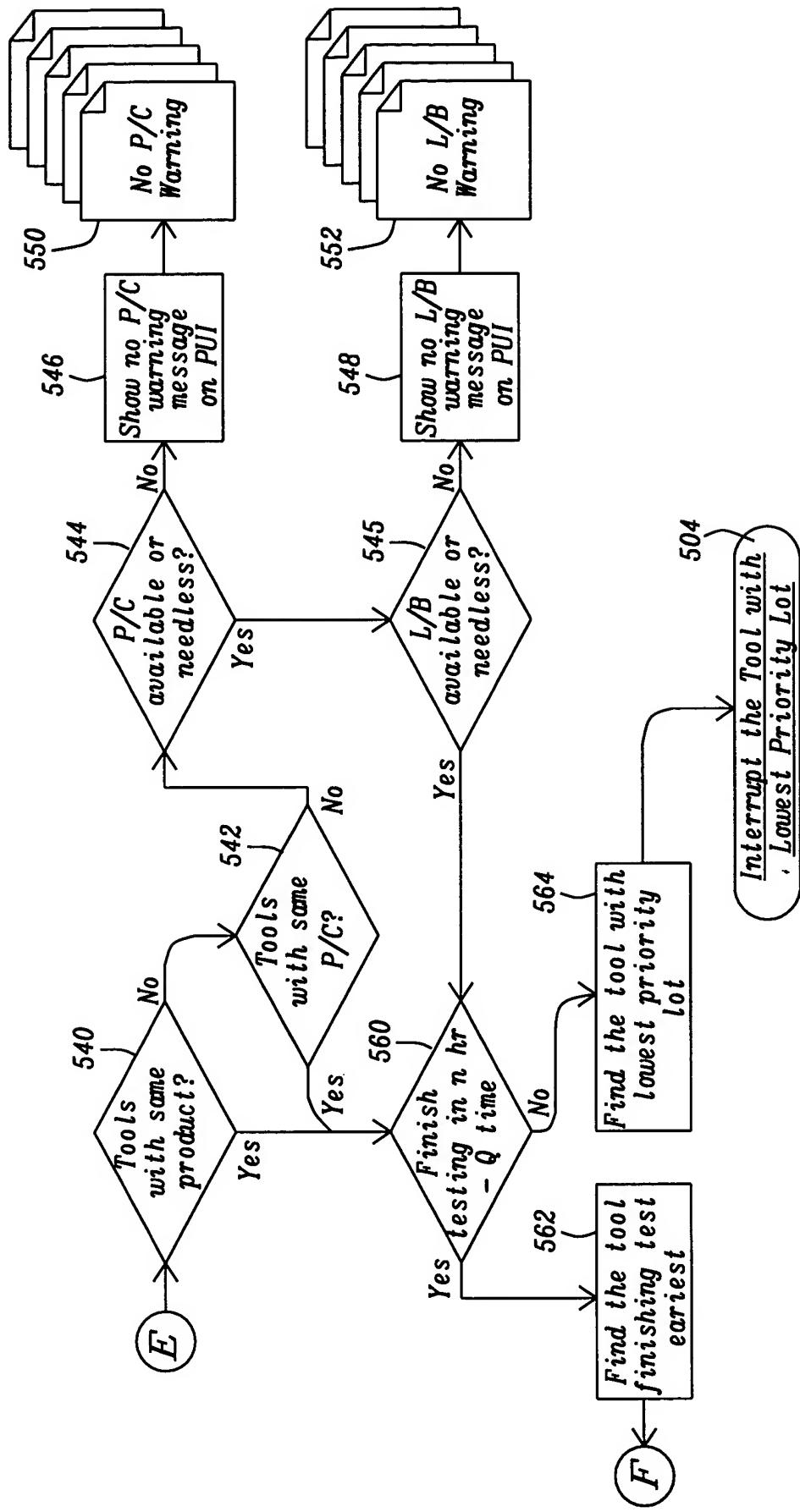


FIG. 5B

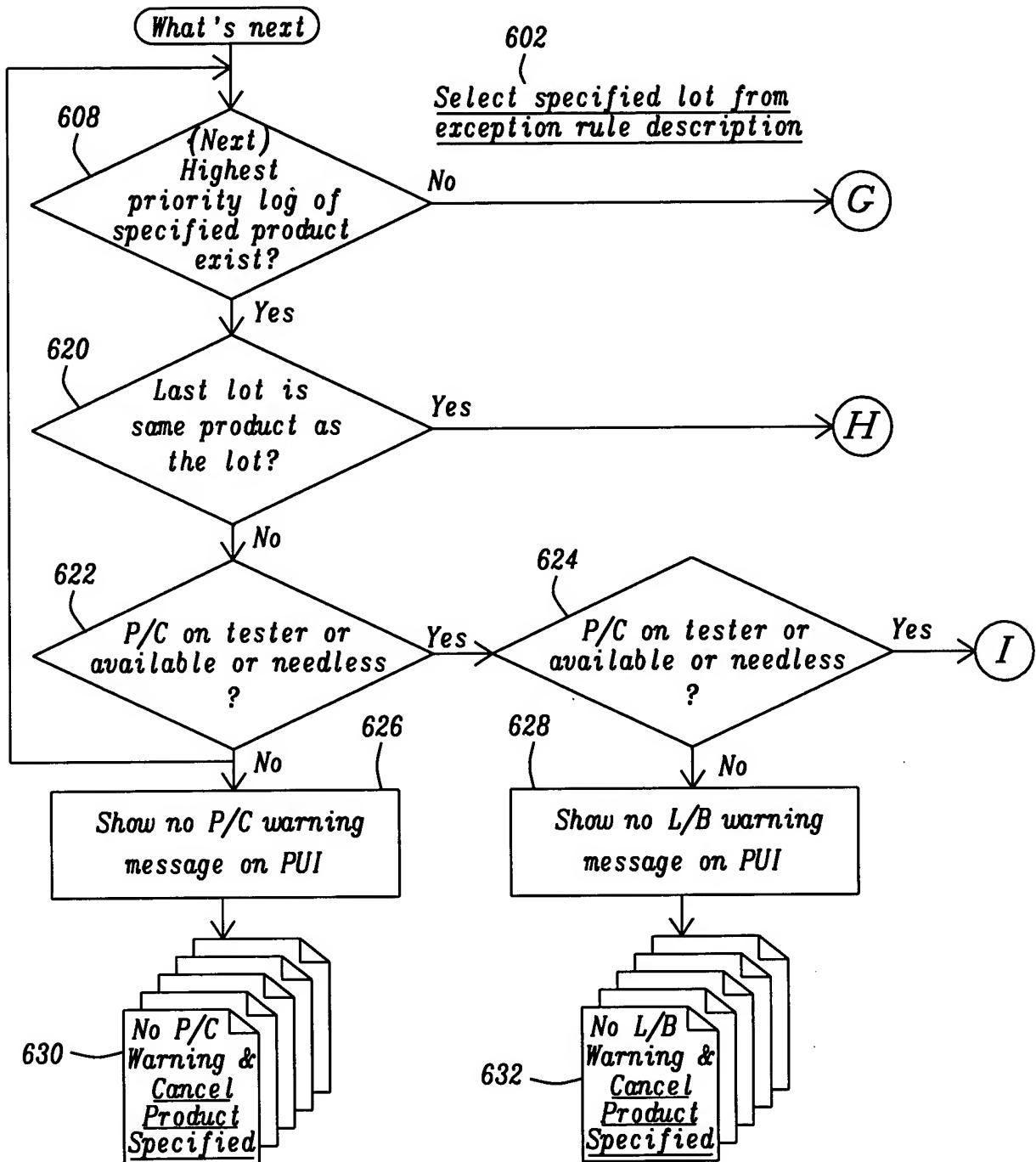


FIG. 6A

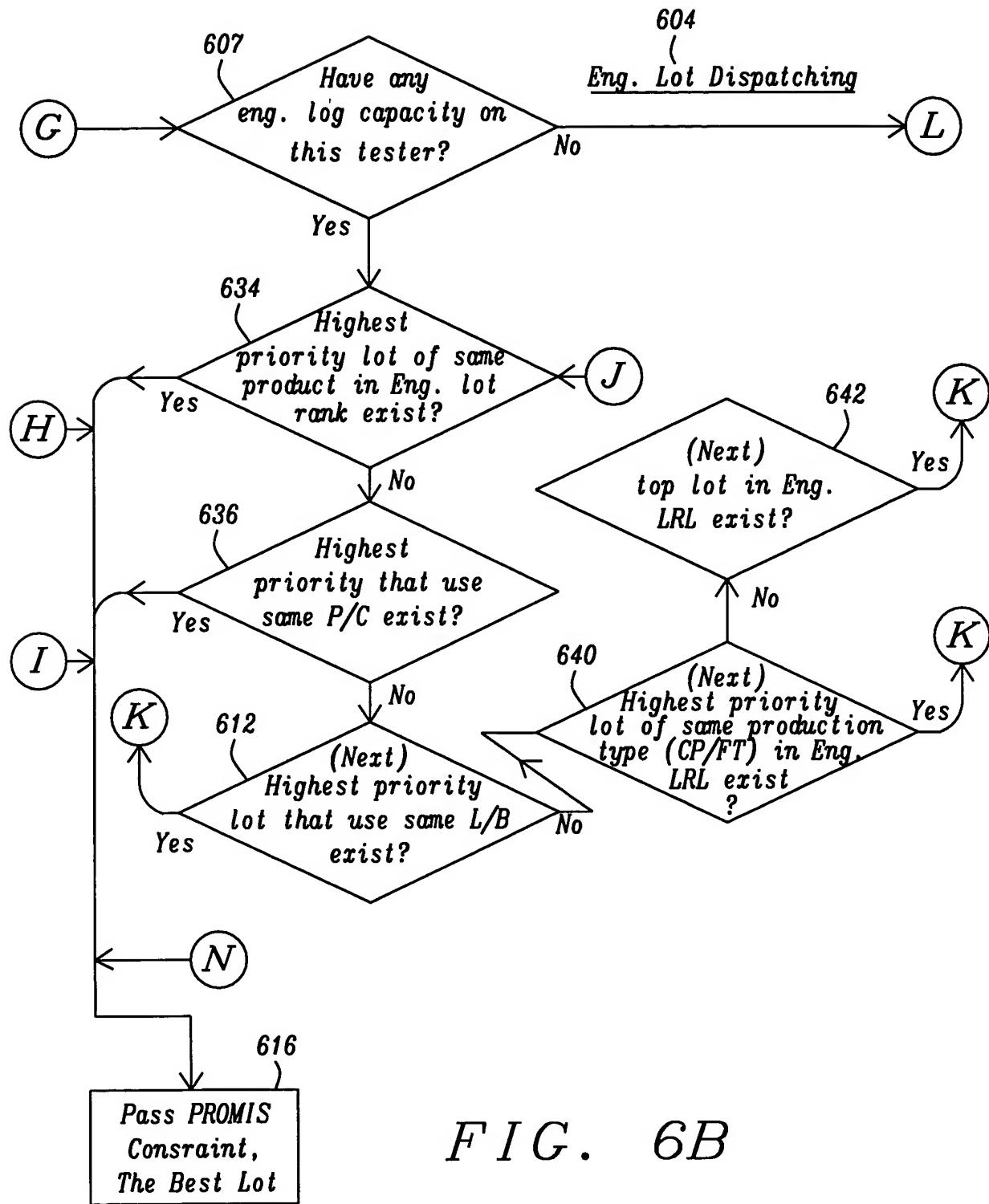


FIG. 6B

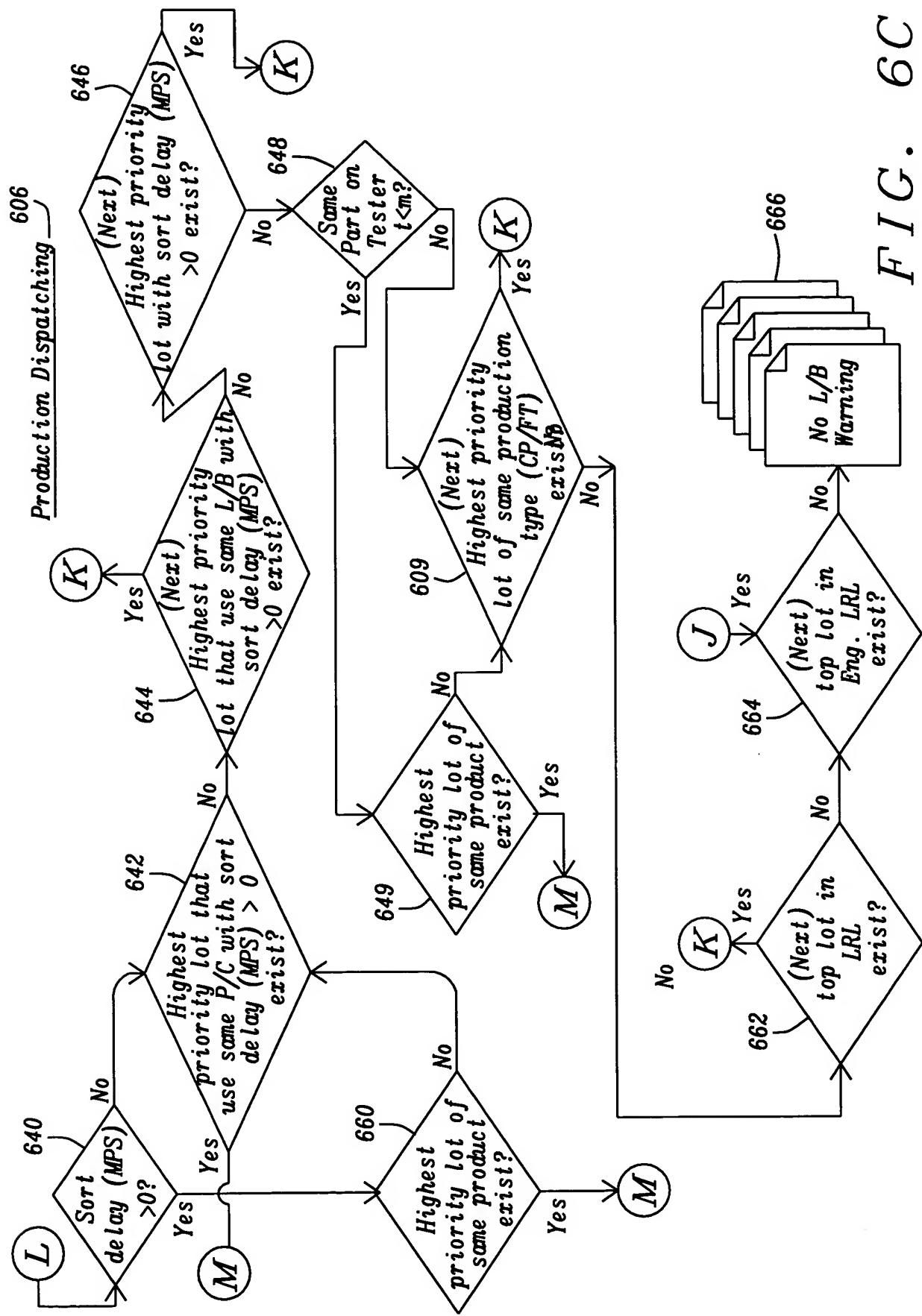


FIG. 6C

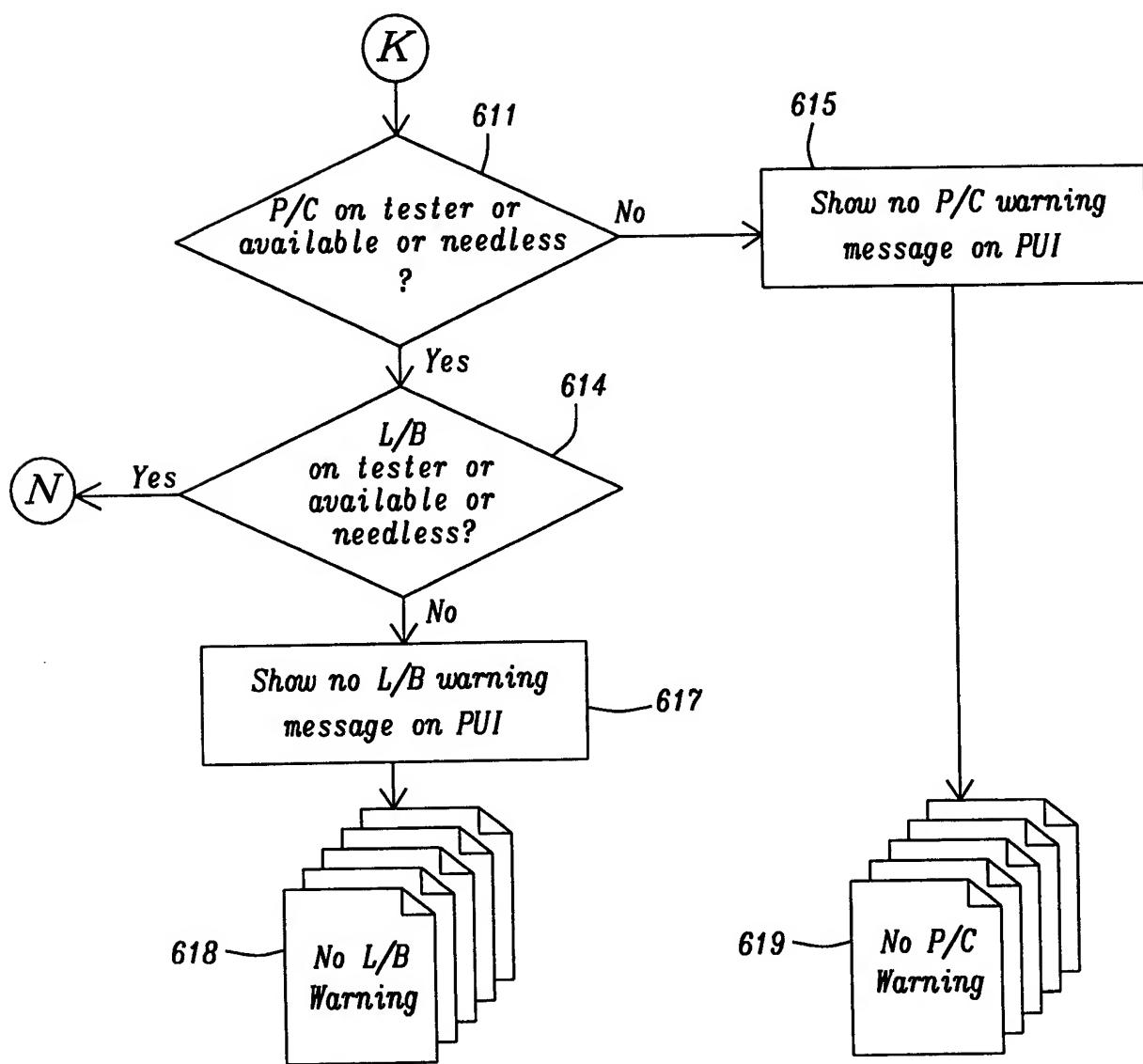


FIG. 6D